

*- Alex J. Adams***5.2**

A p-type silicon material is to have a conductivity of  $\sigma = 1.80 (\Omega\text{-cm})^{-1}$ . If the mobility values are  $\mu_n = 1250 \text{ cm}^2/\text{V-s}$  and  $\mu_p = 380 \text{ cm}^2/\text{V-s}$ , what must be the acceptor impurity concentration in the material?

$$\sigma = e \mu_p N_a$$

$$N_a = \frac{\sigma}{e \mu_p} = \frac{1.80}{1.6 \times 10^{-19} (380)} = 2.96 \times 10^{16} / \text{cm}^3$$

**5.6**

Consider a homogeneous gallium arsenide semiconductor at  $T = 300 \text{ K}$  with  $N_d = 10^{16} \text{ cm}^{-3}$  and  $N_a = 0$ . (a) Calculate the thermal-equilibrium values of electron and hole concentrations. (b) For an applied E-field of  $10 \text{ V/cm}$ , calculate the drift current density. (c) Repeat parts (a) and (b) if  $N_d = 0$  and  $N_a = 10^{16} \text{ cm}^{-3}$ .

$$n_n = \frac{N_d - N_a}{2} + \sqrt{\left(\frac{N_d - N_a}{2}\right)^2 + n_i^2}$$

$$p_n = \frac{n_i^2}{n_n}$$

a.)

$$n_n = \frac{10^{16} - 0}{2} + \sqrt{\left(\frac{10^{16} - 0}{2}\right)^2 + (1.8 \times 10^6)^2}$$

$$n_n = 10^{16} / \text{cm}^3$$

$$p_n = \frac{n_i^2}{n_n} = \frac{(1.8 \times 10^6)^2}{10^{16}} = 3.24 \times 10^{-4} / \text{cm}^3$$

$$b.) J = e \mu_n N_d E = 1.6 \times 10^{-19} (8500) (10^{16}) (10) = 136 \text{ A/cm}^2$$

$$c.) N_a > N_d \quad p\text{-type}$$

$$p_p = \frac{10^{16}}{2} + \sqrt{\left(\frac{10^{16}}{2}\right)^2 + (1.8 \times 10^6)^2} = 10^{16} / \text{cm}^3$$

$$n_p = \frac{p_i^2}{p_p} = \frac{(1.8 \times 10^6)^2}{10^{16}} = 3.24 \times 10^{-4} / \text{cm}^3$$

$$J = 1.6 \times 10^{-19} (400) (10^{16}) (10) = 6.4 \text{ A/cm}^2$$

**5.14** In a particular semiconductor material,  $\mu_n = 1000 \text{ cm}^2/\text{V-s}$ ,  $\mu_p = 600 \text{ cm}^2/\text{V-s}$ , and  $N_C = N_V = 10^{19} \text{ cm}^{-3}$ . These parameters are independent of temperature. The measured conductivity of the intrinsic material is  $\sigma = 10^{-6} (\Omega\text{-cm})^{-1}$  at  $T = 300 \text{ K}$ . Find the conductivity at  $T = 500 \text{ K}$ .

$$\sigma = e (\mu_n + \mu_p) n_i \quad \left| \quad n_i^2 = N_C N_V \exp\left(-\frac{E_g}{kT}\right) \right.$$

conductivity

$$n_i = \frac{6}{e(n_n + n_p)} = \frac{10^{-6}}{(1.2 \times 10^{19})(1000 + 600)} = 3.9 \times 10^7 / \text{cm}^3$$

$$E_g = kT \ln \left( \frac{N_c N_v}{n_i^2} \right) = (8.62 \times 10^{-5})(300) \ln \left( \frac{(10^{19})(10^{19})}{(3.9 \times 10^7)^2} \right) = 1.15 \text{ eV}$$

$$n_i^2 = (10^{19})(10^{19}) \exp \left( \frac{-1.15}{(8.62 \times 10^{-5})(500)} \right) = 2.56 \times 10^{26} / \text{cm}^6$$

$$n_i = \sqrt{2.56 \times 10^{26}} = 1.6 \times 10^{13} / \text{cm}^3$$

$$\sigma = (1.6 \times 10^{-19})(1000 + 600)(1.6 \times 10^{13}) = 4.09 \times 10^{-3} / \Omega \cdot \text{cm}$$

**5.30** The steady-state electron distribution in silicon can be approximated by a linear function of  $x$ . The maximum electron concentration occurs at  $x = 0$  and is  $n(0) = 2 \times 10^{16} \text{ cm}^{-3}$ . At  $x = 0.012 \text{ cm}$ , the electron concentration is  $5 \times 10^{15} \text{ cm}^{-3}$ . If the electron diffusion coefficient is  $D_n = 27 \text{ cm}^2/\text{s}$ , determine the electron diffusion current density.

$$J = eD_n \frac{dn}{dx} = eD_n \left( \frac{n(0) - n(0.012)}{0 - 0.012} \right)$$

$$J = (1.6 \times 10^{-19})(27) \left( \frac{(2 \times 10^{16}) - (5 \times 10^{15})}{0 - 0.012} \right)$$

$$= (1.6 \times 10^{-19})(27)(-1.25 \times 10^{18})$$

$$= -5.4 \text{ A/cm}^2$$

**5.36** The total current in a semiconductor is constant and equal to  $J = -10 \text{ A/cm}^2$ . The total current is composed of a hole drift current and electron diffusion current. Assume that the hole concentration is a constant and equal to  $10^{16} \text{ cm}^{-3}$  and assume that the electron concentration is given by  $n(x) = 2 \times 10^{15} e^{-x/L} \text{ cm}^{-3}$  where  $L = 15 \mu\text{m}$ . The electron diffusion coefficient is  $D_n = 27 \text{ cm}^2/\text{s}$  and the hole mobility is  $\mu_p = 420 \text{ cm}^2/\text{V}\cdot\text{s}$ . Calculate (a) the electron diffusion current density for  $x > 0$ , (b) the hole drift current density for  $x > 0$ , and (c) the required electric field for  $x > 0$ .

$$J = -e D_n \frac{dn}{dx}$$

a.)

$$J = -e D_n \frac{d[2 \times 10^{15} e^{-x/L}]}{dx} = -2 \times 10^{15} (1.6 \times 10^{-19}) (27 e^{-x/(1.5 \times 10^{-4})})$$

$$J_n = -5.76 e^{-[6.7 \times 10^4]x} \text{ A/cm}^2$$

b.) For  $x > 0$

$$J = J_n + J_p = -10 \text{ A/cm}^2$$

$$J_p = -10 - (-5.76 e^{-[6.7 \times 10^4]x})$$

$$J_p = 5.76 e^{-[6.7 \times 10^4]x} - 10 \text{ A/cm}^2$$

c.) For  $x > 0$

$$J_p = e_p \mu_p E$$

$$E = \frac{J_p}{e_p \mu_p} = \frac{5.76 e^{-[6.7 \times 10^4]x} - 10}{1.6 \times 10^{-19} (10^{16}) (420)}$$

$$E = 8.57 e^{-[6.7 \times 10^4]x} - 14.88 \text{ V/cm}$$